

<b>Notice of References Cited</b>	Application/Control No. 10/033,205	Applicant(s)/Patent Under Reexamination KIM, HYUN JIN	
	Examiner David Buttner	Art Unit 1712	Page 1 of 1

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	B	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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